

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/730,910	HAN ET AL.
	Examiner	Art Unit
	Hwei-Siu C. Payer	3724

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See Interference		7-8-05	Payer
Search History			
Flintout			